

## Freeform Search

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<b>Database:</b>	US Pre-Grant Publication Full-Text Database US Patents Full-Text Database US OCR Full-Text Database EPO Abstracts Database JPO Abstracts Database Derwent World Patents Index IBM Technical Disclosure Bulletins
<b>Term:</b>	((measur\$3 or determin\$3) near3 thickness) same (layer or film) same mask\$3 same pattern\$3 same (cmp or polish\$4) same (etch\$3 or remov\$3 or
<b>Display:</b>	<input type="text" value="10"/> Documents in <b>Display Format:</b> <input type="text" value="CIT"/> Starting with Number <input type="text" value="1"/>
<b>Generate:</b> <input type="radio"/> Hit List <input checked="" type="radio"/> Hit Count <input type="radio"/> Side by Side <input type="radio"/> Image	

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### Search History

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DATE: Wednesday, January 26, 2005   [Printable Copy](#)   [Create Case](#)

<u>Set</u> <u>Name</u>	<u>Query</u>	<u>Hit</u> <u>Count</u>	<u>Set</u> <u>Name</u> result set
side by side			
<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ</i>			
<u>L3</u>	((measur\$3 or determin\$3) near3 thickness) same (layer or film) same mask\$3 same pattern\$3 same (cmp or polish\$4) same (etch\$3 or remov\$3 or reduc\$3)	45	<u>L3</u>
<u>L2</u>	thickness same (layer or film) same mask\$3 same pattern\$3 same (cmp or polish\$4) same (etch\$3 or remov\$3 or reduc\$3)	1659	<u>L2</u>
<u>L1</u>	thickness same (layer or film) same mask\$3 same pattern\$3 same (cmp or polish\$4)	1885	<u>L1</u>

END OF SEARCH HISTORY